

**Search Notes**

Application/Control No.

09/617,234

Examiner

CHAN S. PARK

Applicant(s)/Patent under  
Reexamination

YOSHIDA, TAKEHIRO

Art Unit

2625

**SEARCHED**

Class	Subclass	Date	Examiner
358	1.15, 1.13, 407, 438	4/20/2007	CP
358	440,436	4/20/2007	CP
379	100.05	4/20/2007	CP
379	100.09	4/20/2007	CP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

SAME AS  
ABOVE**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR